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**Understanding Embedded - CPLDs (Complex Programmable Logic Devices)** 

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

#### **Applications of Embedded - CPLDs**

Details	
Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	7.5 ns
Voltage Supply - Internal	3V ~ 3.6V
Number of Logic Elements/Blocks	8
Number of Macrocells	128
Number of Gates	2500
Number of I/O	100
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epm7128aeti144-7n

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

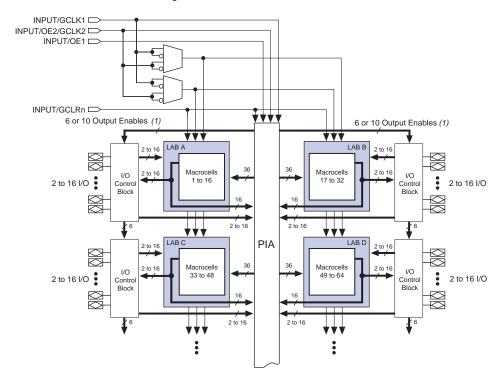


Figure 1. MAX 7000A Device Block Diagram

#### Note:

(1) EPM7032AE, EPM7064AE, EPM7128A, EPM7128AE, EPM7256A, and EPM7256AE devices have six output enables. EPM7512AE devices have 10 output enables.

### **Logic Array Blocks**

The MAX 7000A device architecture is based on the linking of high-performance LABs. LABs consist of 16-macrocell arrays, as shown in Figure 1. Multiple LABs are linked together via the PIA, a global bus that is fed by all dedicated input pins, I/O pins, and macrocells.

Each LAB is fed by the following signals:

- 36 signals from the PIA that are used for general logic inputs
- Global controls that are used for secondary register functions
- Direct input paths from I/O pins to the registers that are used for fast setup times

#### **Expander Product Terms**

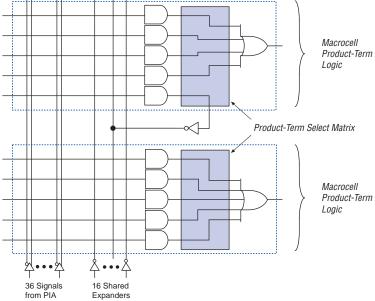
Although most logic functions can be implemented with the five product terms available in each macrocell, more complex logic functions require additional product terms. Another macrocell can be used to supply the required logic resources. However, the MAX 7000A architecture also offers both shareable and parallel expander product terms that provide additional product terms directly to any macrocell in the same LAB. These expanders help ensure that logic is synthesized with the fewest possible logic resources to obtain the fastest possible speed.

#### Shareable Expanders

Each LAB has 16 shareable expanders that can be viewed as a pool of uncommitted single product terms (one from each macrocell) with inverted outputs that feed back into the logic array. Each shareable expander can be used and shared by any or all macrocells in the LAB to build complex logic functions. A small delay ( $t_{SEXP}$ ) is incurred when shareable expanders are used. Figure 3 shows how shareable expanders can feed multiple macrocells.

Shareable expanders can be shared by any or all macrocells in an LAB.

Figure 3. MAX 7000A Shareable Expanders



#### Parallel Expanders

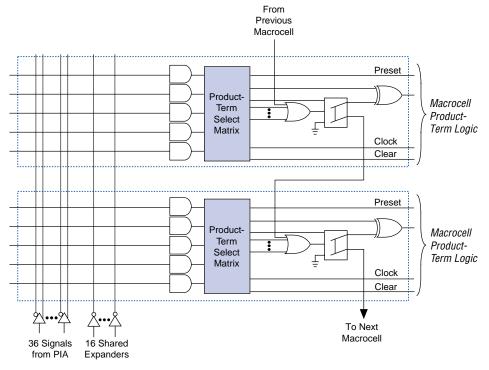
Parallel expanders are unused product terms that can be allocated to a neighboring macrocell to implement fast, complex logic functions. Parallel expanders allow up to 20 product terms to directly feed the macrocell OR logic, with five product terms provided by the macrocell and 15 parallel expanders provided by neighboring macrocells in the LAB.

The compiler can allocate up to three sets of up to five parallel expanders to the macrocells that require additional product terms. Each set of five parallel expanders incurs a small, incremental timing delay ( $t_{PEXP}$ ). For example, if a macrocell requires 14 product terms, the compiler uses the five dedicated product terms within the macrocell and allocates two sets of parallel expanders; the first set includes five product terms, and the second set includes four product terms, increasing the total delay by  $2 \times t_{PEXP}$ .

Two groups of eight macrocells within each LAB (e.g., macrocells 1 through 8 and 9 through 16) form two chains to lend or borrow parallel expanders. A macrocell borrows parallel expanders from lower-numbered macrocells. For example, macrocell 8 can borrow parallel expanders from macrocell 7, from macrocells 7 and 6, or from macrocells 7, 6, and 5. Within each group of eight, the lowest-numbered macrocell can only lend parallel expanders, and the highest-numbered macrocell can only borrow them. Figure 4 shows how parallel expanders can be borrowed from a neighboring macrocell.

Figure 4. MAX 7000A Parallel Expanders

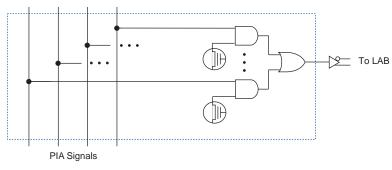
Unused product terms in a macrocell can be allocated to a neighboring macrocell.



### **Programmable Interconnect Array**

Logic is routed between LABs on the PIA. This global bus is a programmable path that connects any signal source to any destination on the device. All MAX 7000A dedicated inputs, I/O pins, and macrocell outputs feed the PIA, which makes the signals available throughout the entire device. Only the signals required by each LAB are actually routed from the PIA into the LAB. Figure 5 shows how the PIA signals are routed into the LAB. An EEPROM cell controls one input to a 2-input AND gate, which selects a PIA signal to drive into the LAB.

Figure 5. MAX 7000A PIA Routing



While the routing delays of channel-based routing schemes in masked or FPGAs are cumulative, variable, and path-dependent, the MAX 7000A PIA has a predictable delay. The PIA makes a design's timing performance easy to predict.

#### I/O Control Blocks

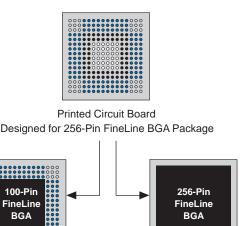
The I/O control block allows each I/O pin to be individually configured for input, output, or bidirectional operation. All I/O pins have a tri-state buffer that is individually controlled by one of the global output enable signals or directly connected to ground or  $V_{CC}.$  Figure 6 shows the I/O control block for MAX 7000A devices. The I/O control block has 6 or 10 global output enable signals that are driven by the true or complement of two output enable signals, a subset of the I/O pins, or a subset of the I/O macrocells.

# SameFrame Pin-Outs

MAX 7000A devices support the SameFrame pin-out feature for FineLine BGA packages. The SameFrame pin-out feature is the arrangement of balls on FineLine BGA packages such that the lower-ball-count packages form a subset of the higher-ball-count packages. SameFrame pin-outs provide the flexibility to migrate not only from device to device within the same package, but also from one package to another. A given printed circuit board (PCB) layout can support multiple device density/package combinations. For example, a single board layout can support a range of devices from an EPM7128AE device in a 100-pin FineLine BGA package to an EPM7512AE device in a 256-pin FineLine BGA package.

The Altera design software provides support to design PCBs with SameFrame pin-out devices. Devices can be defined for present and future use. The software generates pin-outs describing how to lay out a board to take advantage of this migration (see Figure 7).

Figure 7. SameFrame Pin-Out Example



100-Pin FineLine BGA Package (Reduced I/O Count or Logic Requirements) 256-Pin FineLine BGA Package (Increased I/O Count or Logic Requirements)

### Programmable Speed/Power Control

MAX 7000A devices offer a power-saving mode that supports low-power operation across user-defined signal paths or the entire device. This feature allows total power dissipation to be reduced by 50% or more because most logic applications require only a small fraction of all gates to operate at maximum frequency.

The designer can program each individual macrocell in a MAX 7000A device for either high-speed (i.e., with the Turbo Bit<sup>TM</sup> option turned on) or low-power operation (i.e., with the Turbo Bit option turned off). As a result, speed-critical paths in the design can run at high speed, while the remaining paths can operate at reduced power. Macrocells that run at low power incur a nominal timing delay adder ( $t_{LPA}$ ) for the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{EN}$ ,  $t_{SEXP}$ ,  $t_{ACL}$ , and  $t_{CPPW}$  parameters.

### Output Configuration

MAX 7000A device outputs can be programmed to meet a variety of system-level requirements.

#### MultiVolt I/O Interface

The MAX 7000A device architecture supports the MultiVolt I/O interface feature, which allows MAX 7000A devices to connect to systems with differing supply voltages. MAX 7000A devices in all packages can be set for 2.5-V, 3.3-V, or 5.0-V I/O pin operation. These devices have one set of VCC pins for internal operation and input buffers (VCCINT), and another set for I/O output drivers (VCCIO).

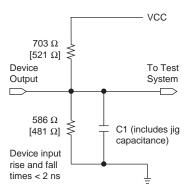
The VCCIO pins can be connected to either a 3.3-V or 2.5-V power supply, depending on the output requirements. When the VCCIO pins are connected to a 2.5-V power supply, the output levels are compatible with 2.5-V systems. When the VCCIO pins are connected to a 3.3-V power supply, the output high is at 3.3 V and is therefore compatible with 3.3-V or 5.0-V systems. Devices operating with V<sub>CCIO</sub> levels lower than 3.0 V incur a slightly greater timing delay of  $t_{OD2}$  instead of  $t_{OD1}$ . Inputs can always be driven by 2.5-V, 3.3-V, or 5.0-V signals.

Table 12 describes the MAX 7000A MultiVolt I/O support.

Table 12. MAX 7000A MultiVolt I/O Support											
V <sub>CCIO</sub> Voltage Input Signal (V) Output Signal (V)											
	2.5	3.3	5.0	2.5	3.3	5.0					
2.5	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>							
3.3	<b>✓</b>	<b>✓</b>	<b>✓</b>		<b>✓</b>	<b>✓</b>					

#### Figure 9. MAX 7000A AC Test Conditions

Power supply transients can affect AC measurements. Simultaneous transitions of multiple outputs should be avoided for accurate measurement. Threshold tests must not be performed under AC conditions. Large-amplitude, fast-groundcurrent transients normally occur as the device outputs discharge the load capacitances. When these transients flow through the parasitic inductance between the device ground pin and the test system ground, significant reductions in observable noise immunity can result. Numbers in brackets are for 2.5-V outputs. Numbers without brackets are for 3.3-V outputs.



## Operating Conditions

Tables 13 through 16 provide information on absolute maximum ratings, recommended operating conditions, operating conditions, and capacitance for MAX 7000A devices.

Table 1	3. MAX 7000A Device Absolu	te Maximum Ratings Note (1)			
Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>CC</sub>	Supply voltage	With respect to ground (2)	-0.5	4.6	V
VI	DC input voltage		-2.0	5.75	V
I <sub>OUT</sub>	DC output current, per pin		-25	25	mA
T <sub>STG</sub>	Storage temperature	No bias	-65	150	°C
T <sub>A</sub>	Ambient temperature	Under bias	-65	135	°C
TJ	Junction temperature	BGA, FineLine BGA, PQFP, and TQFP packages, under bias		135	°C

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>IH</sub>	High-level input voltage		1.7	5.75	V
V <sub>IL</sub>	Low-level input voltage		-0.5	0.8	V
V <sub>OH</sub>	3.3-V high-level TTL output voltage	$I_{OH} = -8 \text{ mA DC}, V_{CCIO} = 3.00 \text{ V}$ (7)	2.4		V
	3.3-V high-level CMOS output voltage	$I_{OH} = -0.1 \text{ mA DC}, V_{CCIO} = 3.00 \text{ V}$ (7)	V <sub>CCIO</sub> – 0.2		V
	2.5-V high-level output voltage	$I_{OH} = -100 \mu A DC, V_{CCIO} = 2.30 V$ (7)	2.1		V
		I <sub>OH</sub> = -1 mA DC, V <sub>CCIO</sub> = 2.30 V (7)	2.0		V
		$I_{OH} = -2 \text{ mA DC}, V_{CCIO} = 2.30 \text{ V}$ (7)	1.7		V
OL	3.3-V low-level TTL output voltage	$I_{OL} = 8 \text{ mA DC}, V_{CCIO} = 3.00 \text{ V } (8)$		0.45	V
	3.3-V low-level CMOS output voltage	$I_{OL} = 0.1 \text{ mA DC}, V_{CCIO} = 3.00 \text{ V } (8)$		0.2	V
	2.5-V low-level output voltage	$I_{OL} = 100 \mu A DC, V_{CCIO} = 2.30 V (8)$		0.2	V
		I <sub>OL</sub> = 1 mA DC, V <sub>CCIO</sub> = 2.30 V (8)		0.4	V
		I <sub>OL</sub> = 2 mA DC, V <sub>CCIO</sub> = 2.30 V (8)		0.7	V
կ	Input leakage current	$V_I = -0.5 \text{ to } 5.5 \text{ V } (9)$	-10	10	μΑ
I <sub>OZ</sub>	Tri-state output off-state current	V <sub>I</sub> = -0.5 to 5.5 V (9)	-10	10	μΑ
R <sub>ISP</sub>	Value of I/O pin pull-up resistor	V <sub>CCIO</sub> = 3.0 to 3.6 V (10)	20	50	kΩ
	during in-system programming	V <sub>CCIO</sub> = 2.3 to 2.7 V (10)	30	80	kΩ
	or during power-up	V <sub>CCIO</sub> = 2.3 to 3.6 V (11)	20	74	kΩ

Table 1	6. MAX 7000A Device Capacital	nce Note (12)							
Symbol	Parameter	Parameter Conditions Min Max Unit							
C <sub>IN</sub>	Input pin capacitance	V <sub>IN</sub> = 0 V, f = 1.0 MHz		8	pF				
C <sub>I/O</sub>	I/O pin capacitance	V <sub>OUT</sub> = 0 V, f = 1.0 MHz		8	pF				

Figure 10 shows the typical output drive characteristics of MAX 7000A devices.

3.3 V MAX 7000AE Devices 2.5 V MAX 7000AE Devices 150 150 100 100 V<sub>CCINT</sub> = 3.3 V Typical I<sub>O</sub> Typical I<sub>O</sub>  $V_{CCINT} = 3.3 V$ Output Output  $V_{CCIO} = 3.3 V$  $V_{CCIO} = 2.5 \text{ V}$ Current (mA) Current (mA) Temperature = 25 °C Temperature = 25 °C 50 50  $I_{\cap H}$ 0 VO Output Voltage (V) Vo Output Voltage (V) EPM7128A & EPM7256A Devices 3.3 V 2.5 V EPM7128A & EPM7256A Devices 120 120  $I_{OL}$  $I_{OL}$ 

Typical I<sub>O</sub>

Output

Temperature = 25°C Current (mA)

V<sub>CCINT</sub> = 3.3 V

 $V_{CCIO} = 3.3 V$ 

VO Output Voltage (V)

Figure 10. Output Drive Characteristics of MAX 7000A Devices

## **Timing Model**

Typical I<sub>O</sub>

Current (mA)

Output

MAX 7000A device timing can be analyzed with the Altera software, a variety of popular industry-standard EDA simulators and timing analyzers, or with the timing model shown in Figure 11. MAX 7000A devices have predictable internal delays that enable the designer to determine the worst-case timing of any design. The software provides timing simulation, point-to-point delay prediction, and detailed timing analysis for device-wide performance evaluation.

80

40

V<sub>CCINT</sub> = 3.3 V

 $V_{CCIO} = 2.5 V$ 

 $I_{OH}$ 

Vo Output Voltage (V)

Temperature = 25 °C

Symbol	Parameter	Conditions			Speed	Grade			Unit	
			-	-4 -7				-10		
			Min	Max	Min	Max	Min	Max		
t <sub>IC</sub>	Array clock delay			1.2		2.0		2.5	ns	
t <sub>EN</sub>	Register enable time			0.6		1.0		1.2	ns	
$t_{GLOB}$	Global control delay			0.8		1.3		1.9	ns	
t <sub>PRE</sub>	Register preset time			1.2		1.9		2.6	ns	
t <sub>CLR</sub>	Register clear time			1.2		1.9		2.6	ns	
$t_{PIA}$	PIA delay	(2)		0.9		1.5		2.1	ns	
$t_{LPA}$	Low-power adder	(6)		2.5		4.0		5.0	ns	

Symbol	Parameter	Conditions			Speed	Grade			Unit
			-	5		7	2.9 1.2 1.6	10	
			Min	Max	Min	Max	Min	Max	
$t_{IN}$	Input pad and buffer delay			0.7		0.9		1.2	ns
t <sub>IO</sub>	I/O input pad and buffer delay			0.7		0.9		1.2	ns
t <sub>FIN</sub>	Fast input delay			2.4		2.9		3.4	ns
t <sub>SEXP</sub>	Shared expander delay			2.1		2.8		3.7	ns
t <sub>PEXP</sub>	Parallel expander delay			0.3		0.5		0.6	ns
$t_{LAD}$	Logic array delay			1.7		2.2		2.8	ns
t <sub>LAC</sub>	Logic control array delay			0.8		1.0		1.3	ns
t <sub>IOE</sub>	Internal output enable delay			0.0		0.0		0.0	ns
t <sub>OD1</sub>	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 3.3 \text{ V}$	C1 = 35 pF		0.9		1.2		1.6	ns
t <sub>OD2</sub>	Output buffer and pad delay, slow slew rate = off $V_{CCIO} = 2.5 \text{ V}$	C1 = 35 pF (5)		1.4		1.7		2.1	ns
t <sub>OD3</sub>	Output buffer and pad delay, slow slew rate = on $V_{CCIO}$ = 2.5 V or 3.3 V	C1 = 35 pF		5.9		6.2		6.6	ns
t <sub>ZX1</sub>	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 3.3 \text{ V}$	C1 = 35 pF		4.0		4.0		5.0	ns
t <sub>ZX2</sub>	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 2.5 \text{ V}$	C1 = 35 pF (5)		4.5		4.5		5.5	ns
t <sub>ZX3</sub>	Output buffer enable delay, slow slew rate = on $V_{CCIO} = 3.3 \text{ V}$	C1 = 35 pF		9.0		9.0		10.0	ns
$t_{XZ}$	Output buffer disable delay	C1 = 5 pF		4.0		4.0		5.0	ns
$t_{SU}$	Register setup time		1.5		2.1		2.9		ns
$t_H$	Register hold time		0.7		0.9		1.2		ns
t <sub>FSU</sub>	Register setup time of fast input		1.1		1.6		1.6		ns
t <sub>FH</sub>	Register hold time of fast input		1.4		1.4		1.4		ns
$t_{RD}$	Register delay			0.9		1.2		1.6	ns
$t_{COMB}$	Combinatorial delay			0.5		0.8		1.2	ns

Symbol	Parameter	Conditions				Speed	Grade				Unit
			-	6	-	7	-1	10	-1	12	
			Min	Max	Min	Max	Min	Max	Min	Max	
$t_{IN}$	Input pad and buffer delay			0.6		0.7		0.9		1.1	ns
$t_{IO}$	I/O input pad and buffer delay			0.6		0.7		0.9		1.1	ns
$t_{FIN}$	Fast input delay			2.7		3.1		3.6		3.9	ns
$t_{SEXP}$	Shared expander delay			2.5		3.2		4.3		5.1	ns
$t_{PEXP}$	Parallel expander delay			0.7		0.8		1.1		1.3	ns
$t_{LAD}$	Logic array delay			2.4		3.0		4.1		4.9	ns
t <sub>LAC</sub>	Logic control array delay			2.4		3.0		4.1		4.9	ns
t <sub>IOE</sub>	Internal output enable delay			0.0		0.0		0.0		0.0	ns
t <sub>OD1</sub>	Output buffer and pad delay, slow slew rate = off V <sub>CCIO</sub> = 3.3 V	C1 = 35 pF		0.4		0.6		0.7		0.9	ns
t <sub>OD2</sub>	Output buffer and pad delay, slow slew rate = off V <sub>CCIO</sub> = 2.5 V	C1 = 35 pF (5)		0.9		1.1		1.2		1.4	ns
t <sub>OD3</sub>	Output buffer and pad delay, slow slew rate = on V <sub>CCIO</sub> = 2.5 V or 3.3 V	C1 = 35 pF		5.4		5.6		5.7		5.9	ns
t <sub>ZX1</sub>	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 3.3 \text{ V}$	C1 = 35 pF		4.0		4.0		5.0		5.0	ns
t <sub>ZX2</sub>	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 2.5 \text{ V}$	C1 = 35 pF (5)		4.5		4.5		5.5		5.5	ns
t <sub>ZX3</sub>	Output buffer enable delay, slow slew rate = on $V_{CCIO} = 3.3 \text{ V}$	C1 = 35 pF		9.0		9.0		10.0		10.0	ns
$t_{XZ}$	Output buffer disable delay	C1 = 5 pF		4.0		4.0		5.0		5.0	ns
t <sub>SU</sub>	Register setup time		1.9		2.4		3.1		3.8		ns
t <sub>H</sub>	Register hold time		1.5		2.2		3.3		4.3		ns
t <sub>FSU</sub>	Register setup time of fast input		0.8		1.1		1.1		1.1		ns
t <sub>FH</sub>	Register hold time of fast input		1.7		1.9		1.9		1.9		ns

Symbol	Parameter	Conditions				Speed	Grade				Unit
			-	6	-	7	-1	10	-1	12	
			Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>RD</sub>	Register delay			1.7		2.1		2.8		3.3	ns
t <sub>COMB</sub>	Combinatorial delay			1.7		2.1		2.8		3.3	ns
t <sub>IC</sub>	Array clock delay			2.4		3.0		4.1		4.9	ns
t <sub>EN</sub>	Register enable time			2.4		3.0		4.1		4.9	ns
t <sub>GLOB</sub>	Global control delay			1.0		1.2		1.7		2.0	ns
t <sub>PRE</sub>	Register preset time			3.1		3.9		5.2		6.2	ns
t <sub>CLR</sub>	Register clear time			3.1		3.9		5.2		6.2	ns
t <sub>PIA</sub>	PIA delay	(2)		0.9		1.1		1.5		1.8	ns
$t_{LPA}$	Low-power adder	(6)		11.0		10.0		10.0		10.0	ns

Table 2	9. EPM7256A External Tir	ning Parame	ters	Note	(1)						
Symbol	Parameter	Conditions				Speed	Grade				Unit
			-	6		7	-1	10		12	
			Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF (2)		6.0		7.5		10.0		12.0	ns
t <sub>PD2</sub>	I/O input to non- registered output	C1 = 35 pF (2)		6.0		7.5		10.0		12.0	ns
t <sub>SU</sub>	Global clock setup time	(2)	3.7		4.6		6.2		7.4		ns
t <sub>H</sub>	Global clock hold time	(2)	0.0		0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input		2.5		3.0		3.0		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input		0.0		0.0		0.0		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF	1.0	3.3	1.0	4.2	1.0	5.5	1.0	6.6	ns
t <sub>CH</sub>	Global clock high time		3.0		3.0		4.0		4.0		ns
t <sub>CL</sub>	Global clock low time		3.0		3.0		4.0		4.0		ns
t <sub>ASU</sub>	Array clock setup time	(2)	8.0		1.0		1.4		1.6		ns
t <sub>AH</sub>	Array clock hold time	(2)	1.9		2.7		4.0		5.1		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF (2)	1.0	6.2	1.0	7.8	1.0	10.3	1.0	12.4	ns
t <sub>ACH</sub>	Array clock high time		3.0		3.0		4.0		4.0		ns
t <sub>ACL</sub>	Array clock low time		3.0		3.0		4.0		4.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	3.0		3.0		4.0		4.0		ns
t <sub>CNT</sub>	Minimum global clock period	(2)		6.4		8.0		10.7		12.8	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(2), (4)	156.3		125.0		93.5		78.1		MHz
t <sub>ACNT</sub>	Minimum array clock period	(2)		6.4		8.0		10.7		12.8	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(2), (4)	156.3		125.0		93.5		78.1		MHz

Symbol	Parameter	Conditions				Speed	Grade				Unit
			-	6	-	7	-1	10	-1	12	
			Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>IN</sub>	Input pad and buffer delay			0.3		0.4		0.5		0.6	ns
t <sub>IO</sub>	I/O input pad and buffer delay			0.3		0.4		0.5		0.6	ns
$t_{FIN}$	Fast input delay			2.4		3.0		3.4		3.8	ns
t <sub>SEXP</sub>	Shared expander delay			2.8		3.5		4.7		5.6	ns
t <sub>PEXP</sub>	Parallel expander delay			0.5		0.6		0.8		1.0	ns
$t_{LAD}$	Logic array delay			2.5		3.1		4.2		5.0	ns
t <sub>LAC</sub>	Logic control array delay			2.5		3.1		4.2		5.0	ns
t <sub>IOE</sub>	Internal output enable delay			0.2		0.3		0.4		0.5	ns
t <sub>OD1</sub>	Output buffer and pad delay, slow slew rate = off V <sub>CCIO</sub> = 3.3 V	C1 = 35 pF		0.3		0.4		0.5		0.6	ns
t <sub>OD2</sub>	Output buffer and pad delay, slow slew rate = off V <sub>CCIO</sub> = 2.5 V	C1 = 35 pF (5)		0.8		0.9		1.0		1.1	ns
t <sub>OD3</sub>	Output buffer and pad delay slow slew rate = on V <sub>CCIO</sub> = 2.5 V or 3.3 V	C1 = 35 pF		5.3		5.4		5.5		5.6	ns
t <sub>ZX1</sub>	Output buffer enable delay slow slew rate = off V <sub>CCIO</sub> = 3.3 V	C1 = 35 pF		4.0		4.0		5.0		5.0	ns
t <sub>ZX2</sub>	Output buffer enable delay slow slew rate = off V <sub>CCIO</sub> = 2.5 V	C1 = 35 pF (5)		4.5		4.5		5.5		5.5	ns
t <sub>ZX3</sub>	Output buffer enable delay slow slew rate = on V <sub>CCIO</sub> = 2.5 V or 3.3 V	C1 = 35 pF		9.0		9.0		10.0		10.0	ns
$t_{XZ}$	Output buffer disable delay	C1 = 5 pF		4.0		4.0		5.0		5.0	ns
t <sub>SU</sub>	Register setup time		1.0		1.3		1.7		2.0		ns
t <sub>H</sub>	Register hold time		1.7		2.4		3.7		4.7		ns
t <sub>FSU</sub>	Register setup time of fast input		1.2		1.4		1.4		1.4		ns
t <sub>FH</sub>	Register hold time of fast input		1.3		1.6		1.6		1.6		ns
$t_{RD}$	Register delay			1.6		2.0		2.7		3.2	ns

Symbol	Parameter	Conditions				Speed	Grade				Unit
			-	6	-	7	-1	10	-1	12	
			Min	Max	Min	Max	Min	Max	Min	Max	
$t_{COMB}$	Combinatorial delay			1.6		2.0		2.7		3.2	ns
t <sub>IC</sub>	Array clock delay			2.7		3.4		4.5		5.4	ns
t <sub>EN</sub>	Register enable time			2.5		3.1		4.2		5.0	ns
t <sub>GLOB</sub>	Global control delay			1.1		1.4		1.8		2.2	ns
t <sub>PRE</sub>	Register preset time			2.3		2.9		3.8		4.6	ns
t <sub>CLR</sub>	Register clear time			2.3		2.9		3.8		4.6	ns
$t_{PIA}$	PIA delay	(2)		1.3		1.6		2.1		2.6	ns
$t_{LPA}$	Low-power adder	(6)		11.0		10.0		10.0		10.0	ns

#### Notes to tables:

- (1) These values are specified under the recommended operating conditions shown in Table 14 on page 28. See Figure 12 for more information on switching waveforms.
- (2) These values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.
- (3) This minimum pulse width for preset and clear applies for both global clear and array controls. The t<sub>LPA</sub> parameter must be added to this minimum width if the clear or reset signal incorporates the t<sub>LAD</sub> parameter into the signal path.
- (4) This parameter is measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (5) Operating conditions:  $V_{CCIO} = 2.5 \pm 0.2 \text{ V}$  for commercial and industrial use.
- (6) The  $t_{LPA}$  parameter must be added to the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{EN}$ ,  $t_{SEXP}$ ,  $t_{ACL}$ , and  $t_{CPPW}$  parameters for macrocells running in low-power mode.

# Power Consumption

Supply power (P) versus frequency ( $f_{MAX}$ , in MHz) for MAX 7000A devices is calculated with the following equation:

$$P = P_{INT} + P_{IO} = I_{CCINT} \times V_{CC} + P_{IO}$$

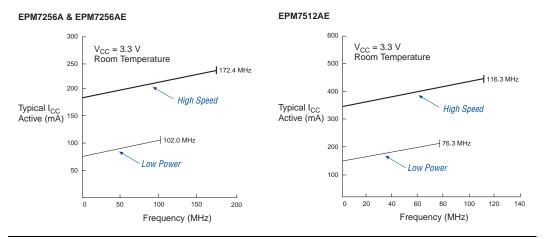
The  $P_{\rm IO}$  value, which depends on the device output load characteristics and switching frequency, can be calculated using the guidelines given in *Application Note 74 (Evaluating Power for Altera Devices)*.

The  $I_{CCINT}$  value depends on the switching frequency and the application logic. The  $I_{CCINT}$  value is calculated with the following equation:

$$I_{CCINT} =$$

$$(A \times MC_{TON}) + [B \times (MC_{DEV} - MC_{TON})] + (C \times MC_{USED} \times f_{\boldsymbol{MAX}} \times \boldsymbol{tog_{LC}})$$

Figure 13. I<sub>CC</sub> vs. Frequency for MAX 7000A Devices (Part 2 of 2)



## Device Pin-Outs

See the Altera web site (http://www.altera.com) or the *Altera Digital Library* for pin-out information.

Figures 14 through 23 show the package pin-out diagrams for MAX 7000A devices.

Figure 14. 44-Pin PLCC/TQFP Package Pin-Out Diagram

Package outlines not drawn to scale.

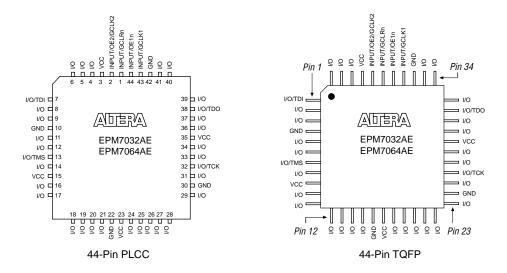
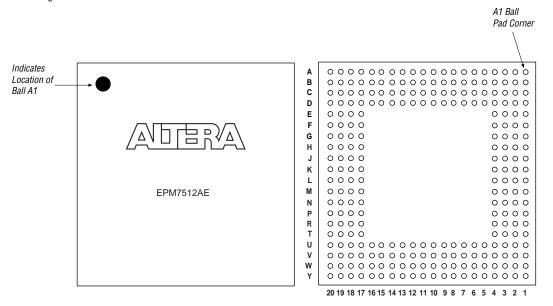


Figure 22. 256-Pin BGA Package Pin-Out Diagram

Package outline not drawn to scale.



#### Version 4.3

The following changes were made in the MAX 7000A Programmable Logic Device Data Sheet version 4.3:

- Added extended temperature devices to document
- Updated Table 14.

#### Version 4.2

The following changes were made in the MAX 7000A Programmable Logic Device Data Sheet version 4.2:

- Removed *Note* (1) from Table 2.
- Removed *Note* (4) from Tables 3 and 4.

#### Version 4.1

The following changes were made in the MAX 7000A Programmable Logic Device Data Sheet version 4.1:

- Updated leakage current information in Table 15.
- Updated Note (9) of Table 15.
- Updated *Note* (1) of Tables 17 through 30.



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Altera customers are advised to obtain the latest version of device specifications before relying on any published information and before placing orders for products or services.

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